

Notice of References Cited	Application/Control No. 10/523,854	Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner Randall Winston	Art Unit 1655	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0025348	02-2002	Basu et al.	424/735
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP355127317A	10-1980	Japan	Sugihara et al.	
	O	JP409143087A	06-1997	Japan	Yamamoto	
	P	JP 2001089346A	04-2001	Japan	Wakasaya	
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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